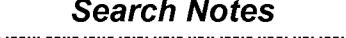


Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/912,721	CHEN ET AL.	
	Examiner	Art Unit	
	JOHN J. LEE	2618	

Search Notes



Application/Control No.

09/912,721

Examiner

JOHN J. LEE

**Applicant(s)/Patent under
Reexamination**

CHEN ET AL.

Art Unit

2618

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)